

**Amendments to the Claims:**

Please amend the claims as follows:

Claim 1 (Currently Amended): A probe device for measuring characteristics of an electromagnetic field radiated by an electromagnetic source under test, said device comprising a ~~radiating~~ wave reception element, and a probe mount on which said support is fastened, and further comprising a screen carried by said support and interposed between said ~~radiating~~ wave reception element and said probe mount for reflecting the beams impinging upon it from said source under test so as to re-emit and scatter them as diverging beams into space.

Claim 2 (Currently Amended): A probe device as claimed in claim 1, wherein said screen is shaped and arranged around a central axis of symmetry also constituting a sighting axis for said ~~radiating~~ wave reception element when pointing the ~~measuring~~ probe device along determined measuring directions so that said screen is effective to then direct said diverging beams away ~~from~~ from said central axis.

Claim 3 (Currently Amended): A probe device as claimed in claim 1, wherein said screen is so shaped that when said electromagnetic radiation source under test is disposed on a measurement site comprising an ~~anechoic~~ anechoic chamber enclosing said source and said device within walls made of a material absorbing [[the]] wave lengths associated with the electromagnetic radiations ~~from~~ from said source and said device is used as a measuring probe device for determining the characteristics of said source under test, said diverging beams re-emitted by said screen are directed towards said absorbing walls.

Claim 4 (Original): A probe device as claimed in claim 1, as associated with a movable carrying device for supporting and moving it to scan a predetermined surface when it is used as a measuring probe device for determining the characteristics of said source under test and the latter is fixed.

Claim 5 (Original): A probe device as claimed in claim 4, wherein said predetermined surface is planar.

Claim 6 (Original): A probe device as claimed in claim 4, wherein said predetermined surface is cylindrical.

Claim 7 (Currently Amended): A probe device as claimed in claim 1, wherein said screen is shaped and arranged around a central axis of symmetry to be effective to direct said diverging beams way form said central axis, said ~~radiating~~ wave reflecting element is a conical horn, said support is a wave guide with a circular cross section arranged as an extension of said conical horn with same central axis of symmetry, and said mount is a rectangular plate transverse to said central axis.

Claim 8 (Original): A probe device as claimed in claim 7, wherein said screen is a conic skirt having a circular cross section around said axis, inclined by an acute angle with respect to said central axis towards said probe mount.

Claim 9 (Original): A probe device as claimed in claim 8, wherein said acute angle equals 45 degrees.

Claim 10 (Currently Amended): A probe device as claimed in claim 7, wherein said ~~radiating~~ wave reception element, said support, said probe mount, and said screen are made of a metallic material.

Claim 11 (Original): A probe device as claimed in claim 1 for use with an antenna emitting within the hyper frequency range as said electromagnetic source for measuring its radiation diagram.

Claim 12 (Currently Amended): A probe device as claimed in claim 7 ~~[[or 8]]~~, wherein said ~~radiating~~ wave reception element, said support, said probe mount, and said screen are made of a metallic material.

Claim 13 (Currently Amended): A probe device as claimed in claim 7 ~~[[or 8]]~~ for use with an antenna emitting within the hyper frequency range as said electromagnetic source for measuring its radiation diagram.

Claim 14 (New): A measuring probe configured to measure characteristics of an electromagnetic field radiated by an electromagnetic source, the probe comprising:

a wave reception element;

a support configured to support the wave reception element and to be mounted to a probe mount;

a screen interposed between the wave reception element and the probe mount and configured to reflect beams from the electromagnetic source by scattering.

Claim 15 (New): The probe according to Claim 14, wherein the screen is configured about a central axis of symmetry along at least one predetermined measuring direction so that the screen scatters the beams away from the central axis.

Claim 16 (New): The probe according to Claim 14, wherein when the probe is used in an anechoic chamber including absorbent walls configured to absorb wavelengths associated with the electromagnetic source, the screen is configured to scatter the beams toward the absorbent walls.

Claim 17 (New): The probe according to Claim 14, further comprising a moveable carrying device configured to support and move the probe when scanning a predetermined surface.

Claim 18 (New): The probe according to Claim 17, wherein the predetermined surface includes a planar surface.

Claim 19 (New): The probe according to Claim 17, wherein the predetermined surface includes a cylindrical surface.

Claim 20 (New): The probe according to Claim 15, wherein the wave reflecting element includes a conical horn.

Claim 21 (New): The probe according to Claim 20, wherein the support includes a wave guide having a circular cross section configured as an extension of the conical horn.

Claim 22 (New): The probe according to Claim 21, wherein the probe mount includes a rectangular plate transverse to the central axis.

Claim 23 (New): The probe according to Claim 14, wherein the screen includes a conical skirt having a circular cross section around the central axis, inclined by an acute angle relative to the central axis toward the probe mount.

Claim 24 (New): The probe according to Claim 23, wherein the acute angle is 45 degrees.

Claim 25 (New): The probe according to Claim 14, wherein at least one of the wave reception element, the support, the probe mount, and the screen includes a metallic material.